Ultra-Low Jitter, Low Skew 1:12 LVCMOS/LVTTL Fanout Buffer

The NB3V8312C is a high performance, low skew L VCMOS fanout buffer which can distribute 12 ultra –low jitter clocks from an LVCMOS/LVTTL input up to 250 MHz.

The 12 LVCMOS output pins drive 50 Ω series or parallel terminated transmission lines. The outputs can also be disabled to a high impedance (tri–stated) via the OE input, or enabled when High.

The NB3V8312C provides an enable input, CLK_EN pin, which synchronously enables or disables the clock outputs while in the LOW state. Since this input is internally synchronized to the input clock, changing only when the input is LOW, potential output glitching or runt pulse generation is eliminated.

Separate V_{DD} core and V_{DDO} output supplies allow the output buffers to operate at the same supply as the V_{DD} (V_{DD} = V_{DDO}) or from a lower supply voltage. Compared to single –supply operation, dual supply operation enables lower power consumption and output–level compatibility.

The V_{DD} core supply voltage can be set to 3.3 V , 2.5 V or 1.8 V, while the V_{DDO} output supply voltage can be set to 3.3 V , 2.5 V, or 1.8 V, with the constraint that V_{DD} \geq V_{DDO}.

This buffer is ideally suited for various networking, telecom, server and storage area networking, RRU LO reference distribution, medical and test equipment applications.

Features

• Power Supply Modes	3:
----------------------	----

V _{DD} (Core)	/ V _{DDO} (Outputs)
3.3 V	/ 3.3 V
3.3 V	/ 2.5 V
3.3 V	/ 1.8 V
2.5 V	/ 2.5 V
2.5 V	/ 1.8 V
1.8 V	/ 1.8 V

- 250 MHz Maximum Clock Frequency
- Accepts LVCMOS, LVTTL Clock Inputs
- LVCMOS Compatible Control Inputs
- 12 LVCMOS Clock Outputs
- Synchronous Clock Enable
- Output Enable to High Z State Control
- 150 ps Max. Skew Between Outputs
- Temp. Range -40° C to $+85^{\circ}$ C
- 32-pin LQFP and QFN Packages
- These are Pb–Free Devices



ON Semiconductor®

http://onsemi.com





LQFP-32 FA SUFFIX CASE 873A

QFN32 MN SUFFIX CASE 488AM

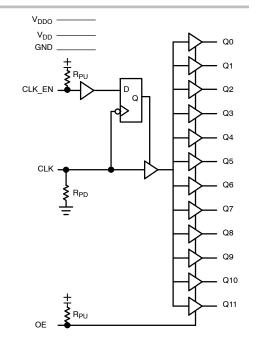


Figure 1. Simplified Logic Diagram

ORDERING AND MARKING INFORMATION

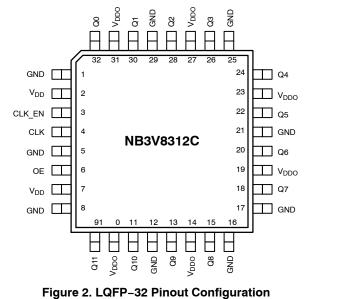
See detailed ordering and shipping information on page 9 of this data sheet.

Applications

- Networking
- Telecom
- Storage Area Network

End Products

- Servers
- Routers
- Switches



(Top View)

Table 1. PIN DESCRIPTION

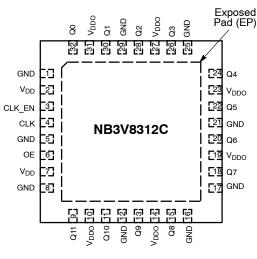


Figure 3. QFN32 Pinout Configuration (Top View)

			Open	
Pin	Name	I/O	Default	Description
1, 5, 8, 12, 16, 17, 21, 25, 29	GND	Power		Ground, Negative Power Supply
2, 7	VDD	Power		Positive Supply for Core and Inputs
3	CLK_EN	Input	High	Synchronous Clock Enable Input. When High, outputs are enabled. When Low, outputs are disabled Low. Internal Pullup Resistor.
4	CLK	Input	Low	Single-ended Clock input; LVCMOS/LVTTL. Internal Pull-down Resistor.
6	OE	Input	High	Output Enable. Internal Pullup Resistor.
9, 11, 13, 15, 18, 20, 22, 24, 26, 28, 30, 32	Q11, Q10, Q9, Q8, Q7, Q6, Q5, Q4, Q3, Q2, Q1, Q0	Output		Single-ended LVCMOS/LVTTL outputs
10, 14, 19, 23, 27, 31	VDDO	Power		Positive Supply for Outputs
_	EP	_	_	The Exposed Pad (EP) on the package bottom is ther- mally connected to the die for improved heat transfer out of package. The exposed pad must be attached to a heat-sinking conduit. The pad is connected to the die and must only be connected electrically to GND on the PC board.

1. All VDD, VDDO and GND pins must be externally connected to a power supply to guarantee proper operation. Bypass each supply pin with 0.01 μ F to GND.

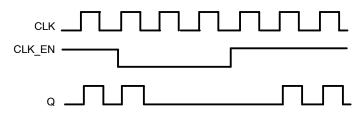


Figure 4. CLK_EN Control Timing Diagram

Table 2. OE, CLK_EN FUNCTION TABLES

	Outputs		
OE	CLK_EN (Note 2)	CLK	Q[0:11]
0	Х	Х	Hi–Z
1	0	Х	Low
1	1	0	Low
1	1	1	High

2. The CLK_EN control input synchronously enables or disables the outputs as shown in Figure 4. This control latches on the falling edge of the selected input CLK. When CLK_EN is LOW, the outputs are disabled in a LOW state. When CLK_EN is HIGH, the outputs are enabled as shown. CLK_EN to CLK Set up and Hold times must be satisfied.

Table 3. ATTRIBUTES (Note 3)

Characteristics	Value
Internal Input Pullup (R_{PU}) and Pulldown (R_{PD}) Resistor	50 kΩ
Input Capacitance, C _{IN}	4 pF
Power Dissipation Capacitance, C _{PD} (per Output)	20 pF
R _{OUT}	8 Ω
ESD Protection Human Body Model Machine Model	> 1.5 kV > 200 V
Moisture Sensitivity, Indefinite Time Out of Drypack (Note 3)	Level 1
Flammability Rating Oxygen Index	UL-94 code V-0 A 1/8" 28 to 34
Transistor Count	464 Devices
Meets or exceeds JEDEC Spec EIA/JESD78 IC Latchup Test	

3. For additional information, see Application Note AND8003/D.

Table 4. MAXIMUM RATINGS (Note 4)

Symbol	Parameter	Condition		Rating	Unit
V _{DD} / V _{DDO}	Positive Power Supply	GND = 0 V		4.6	V
VI	Input Voltage			$-0.5\leqV_{I}\leqV_{DD}+0.5$	V
T _{stg}	Storage Temperature Range			−65 to +150	°C
θ_{JA}	Thermal Resistance (Junction-to-Ambient) (Note 5)	0 lfpm 500 lfpm	LQFP-32 LQFP-32	80 55	°C/W °C/W
θις	Thermal Resistance (Junction-to-Case) (Note 5)	Standard Board	LQFP-32 LQFP-32	12–17	°C/W
θ_{JA}	Thermal Resistance (Junction-to-Ambient) (Note 5)	0 lfpm 500 lfpm	QFN - 32 QFN - 32	31 27	°C/W
θ _{JC}	Thermal Resistance (Junction-to-Case) (Note 5)	Standard Board	QFN-32	12	°C/W

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only . Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and not valid simultaneously. If stress limits are exceeded device functional operation is not implied, damage may occur and reliability may be affected.
 JEDEC standard multilayer board – 2S2P (2 signal, 2 power).

Symbol	Chara	cteristics	Conditions	Min	Тур	Max	Unit	
	Input High Voltage		V _{DD} = 3.465 V	2.0		V _{DD} + 0.3	V	
V _{IH}			V _{DD} = 2.625 V	1.7		V _{DD} + 0.3	V	
			V _{DD} = 2.0 V	0.65 x V _{DD}		V _{DD} + 0.3	V	
			V _{DD} = 3.465 V	-0.3		1.3	V	
V _{IL}	Input Low Vol	tage	V _{DD} = 2.625 V	-0.3		0.7	V	
٠١٢			V _{DD} = 2.0 V	-0.3		0.35 x V _{DD}	V	
	Input High	CLK				150		
I _{IH}	Current	OE, CLK_EN	$V_{DD} = V_{IN} = 3.465 \text{ V or } 2.625 \text{ V or } 2.0 \text{ V}$			5	μΑ	
	Input Low	CLK	V _{DD} = 3.465 V or 2.625 V or 2.0 V, V _{IN} = 0 V	-5			۸	
IIL	Current	OE, CLK_EN	$v_{DD} = 3.465$ V of 2.625 V of 2.0 V, $v_{IN} = 0$ V	-150			μA	
			V _{DDO} = 3.3 V ±5%	2.6				
			V _{DDO} = 2.5 V ±5%	1.8				
			V_{DDO} = 2.5 V ±5%; I _{OH} = -1 mA	2.0			1	
V _{OH}	Output High V	/oltage (Note 6)	V _{DDO} = 1.8 V ±0.2 V	V _{DD} - 0.4			V	
			V _{DDO} = 1.8 V ±0.2 V; I _{OH} = -100 μA	V _{DD} – 0.2				
	V _{DDO} = 3. 3V ±5%		V _{DDO} = 3. 3V ±5%			0.5		
			V _{DDO} = 2.5 V ±5%			0.45		
V _{OL}	Output Low V	oltage (Note 6)	$V_{DDO} = 2.5 \text{ V} \pm 5\%; \text{ I}_{OL} = 1 \text{ mA}$			0.4	V	
			V _{DDO} = 1.8 V ±0.2 V			0.35		
			V_{DDO} = 1.8 V ±0.2 V; I _{OL} = 100 µA			0.2		

Table 5. LVCMOS/LVTTL DC CHARACTERISTICS (T_A = -40° C to $+85^{\circ}$ C)

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

6. Outputs terminated 50 Ω to V_DDO/2 unless otherwise specified. See Figure 7.

Table 6. POWER SUPPLY DC CHARACTERISTICS, (T_A = -40 $^{\circ}\mathrm{C}$ to +85 $^{\circ}\mathrm{C}$)

V _{DD} (Core)	V _{DDO} (Outputs)	Min	Тур	Max	Unit
3.3 V ±5%	3.3 V ±5%			10	mA
3.3 V ±5%	2.5 V ±5%			10	mA
3.3 V ±5%	$1.8~V\pm0.2V$			10	mA
2.5 V ±5%	2.5 V ±5%			10	mA
2.5 V ±5%	$1.8~V\pm0.2V$			10	mA
1.8 V ± 0.2 V	$1.8~V\pm0.2V$			10	mA

Symbol	Characteristic	Min	Тур	Max	Unit
f _{MAX}	$\begin{array}{c} \mbox{Maximum Operating Frequency} & \mbox{V}_{DD} \ / \ \mbox{V}_{DD} \ \\ \mbox{3.3 V } \pm 5\% \ / \ \mbox{3.3 V } \pm 5\% \ \\ \mbox{3.3 V } \pm 5\% \ / \ \mbox{2.5 V } \pm 5\% \ \\ \mbox{3.3 V } \pm 5\% \ / \ \mbox{1.8 V } \pm \ \mbox{0.2 V} \ \\ \mbox{2.5 V } \pm 5\% \ / \ \mbox{2.5 V } \pm 5\% \ \\ \mbox{2.5 V } \pm 5\% \ / \ \mbox{1.8 V } \pm \ \mbox{0.2 V} \ \\ \mbox{1.8 V } \pm \ 1$	250 250 200 250 200 200			MHz
tpLH	$\begin{array}{c} \mbox{Propagation Delay, Low to High; (Note 8)} & \mbox{V}_{DD} \ / \ \mbox{V}_{DD} \ / \ \mbox{V}_{DD} \ \\ \mbox{3.3 V } \pm 5\% \ / \ \mbox{3.3 V } \pm 5\% \ \\ \mbox{3.3 V } \pm 5\% \ / \ \mbox{2.5 V } \pm 5\% \ \\ \mbox{3.3 V } \pm 5\% \ / \ \mbox{2.5 V } \pm 5\% \ \\ \mbox{2.5 V } \pm 5\% \ / \ \mbox{2.5 V } \pm 5\% \ \\ \mbox{2.5 V } \pm 5\% \ / \ \mbox{1.8 V } \pm \ \mbox{0.2 V} \ \\ \mbox{1.8 V } \pm \ \mbox{0.2 V} \ \ \mbox{1.8 V } \pm \ \mbox{0.2 V} \ \end{array}$	0.9 1.0 1.3 1.3 2.4		2.2 2.3 3.0 3.1 3.5 4.2	ns
t _{jit}	$\begin{array}{llllllllllllllllllllllllllllllllllll$		30 40 50 20 100 130		fs
t _{sk(o)}	$\begin{array}{c c} \mbox{Output-to-output skew; (Note 9); Figure 6} & V_{DD} \ / \ V_{DDO} \\ 3.3 \ V \pm 5\% \ / \ 3.3 \ V \pm 5\% \\ 3.3 \ V \pm 5\% \ / \ 2.5 \ V \pm 5\% \\ 3.3 \ V \pm 5\% \ / \ 1.8 \ V \pm 0.2 \ V \\ 2.5 \ V \pm 5\% \ / \ 2.5 \ V \pm 5\% \\ 2.5 \ V \pm 5\% \ / \ 1.8 \ V \pm 0.2 \ V \\ 1.8 \ V \pm 0.2 \ V \ / \ 1.8 \ V \pm 0.2 \ V \end{array}$			125 135 145 150 150 140	ps
t _{sk(pp)}	$\begin{array}{c} \mbox{Part-to-Part Skew; (Note 10)} & \mbox{V}_{DD} \ / \ V_{DDO} \\ 3.3 \ V \pm 5\% \ / \ 3.3 \ V \pm 5\% \\ 3.3 \ V \pm 5\% \ / \ 2.5 \ V \pm 5\% \\ 3.3 \ V \pm 5\% \ / \ 1.8 \ V \pm 0.2 \ V \\ 2.5 \ V \pm 5\% \ / \ 2.5 \ V \pm 5\% \\ 2.5 \ V \pm 5\% \ / \ 1.8 \ V \pm 0.2 \ V \\ 1.8 \ V \pm 0.2 \ V \ 1.8 \ V \pm 0.2 \ V \end{array}$			250 250 250 250 250 250 250	ps
t _r /t _f	$\begin{array}{c} \text{Output rise and fall times} & & & & & & & & & & $	200 200 200 200 200 200		700 700 700 700 700 800	ps
ODC	$ \begin{array}{c c} \mbox{Output Duty Cycle (Note 11)} & \mbox{V}_{DD} \ / \ V_{DDO} \\ f \leq 200 \ \mbox{MHz}, \ 3.3 \ V \pm 5\% \ / \ 3.3 \ V \pm 5\% \\ f \leq 150 \ \mbox{MHz}, \ 3.3 \ V \pm 5\% \ / \ 2.5 \ V \pm 5\% \\ f \leq 100 \ \mbox{MHz}, \ 3.3 \ V \pm 5\% \ / \ 1.8 \ V \pm 0.2 \ V \\ f \leq 150 \ \mbox{MHz}, \ 2.5 \ V \pm 5\% \ / \ 2.5 \ V \pm 5\% \\ f \leq 100 \ \mbox{MHz}, \ 2.5 \ V \pm 5\% \ / \ 1.8 \ V \pm 0.2 \ V \\ f \leq 100 \ \mbox{MHz}, \ 1.8 \ V \pm 0.2 \ V \ f \leq 100 \ \mbox{MHz}, \ 1.8 \ V \pm 0.2 \ V \\ \end{array} $	45 45 45 45 45 45 45		55 55 55 55 55 55 55	%

Table 7. AC CHARACTERISTICS ($T_A = -40^{\circ}C$ to +85°C) (Note 7)

All parameters measured at $\ensuremath{f_{\text{MAX}}}$ unless noted otherwise.

Outputs loaded with 50 Ω to V_{DDO}/2; see Figure 7. CLOCK input with 50% duty cycle; minimum input amplitude = 1.2 V at V_{DD} = 3.3 V, 1.0 V at V_{DD} = 2.5 V, V_{DD}/2 at V_{DD} = 1.8 V.
 Measured from the V_{DD}/2 of the input to V_{DDO}/2 of the output.
 Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at V_{DDO}/2.
 Defined as skew between outputs on different devices operating at the same supply voltage and with equal load conditions.

Using the same type of input on each device, the output is measured at V_{DDO}/2.

11. Clock input with 50% duty cycles, rail-to-rail amplitude and $t_r/t_f = 500$ ps.

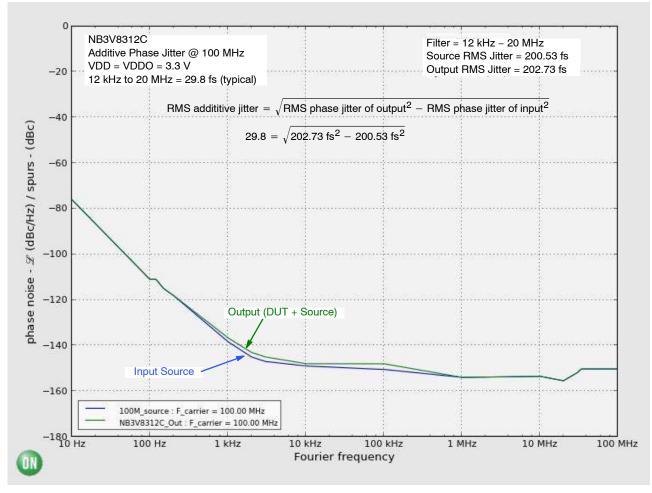


Figure 5. Typical Phase Noise Plot at f_{carrier} = 100 MHz at an Operating Voltage of 3.3 V, Room Temperature

The above phase noise data was captured using Agilent E5052A/B. The data displays the input phase noise and output phase noise used to calculate the additive phase jitter at a specified integration range. The RMS Phase Jitter contributed by the device (integrated between 12 kHz and 20 MHz) is 29.8 fs.

The additive phase jitter performance of the fanout buffer is highly dependent on the phase noise of the input source.

To obtain the most accurate additive phase noise measurement, it is vital that the source phase noise be notably lower than that of the DUT. If the phase noise of the source is greater than the device under test output, the source noise will dominate the additive phase jitter calculation and lead to an artificially low result for the additive phase noise measurement within the integration range. The Figure above is a good example of the NB3V8312C source generator phase noise having a significantly higher floor such that the DUT output results in an additive phase jitter of 29.8 fs.

RMS addititive jitter =
$$\sqrt{\text{RMS phase jitter of output}^2 - \text{RMS phase jitter of input}^2}$$

29.8 = $\sqrt{202.73 \text{ fs}^2 - 200.53 \text{ fs}^2}$

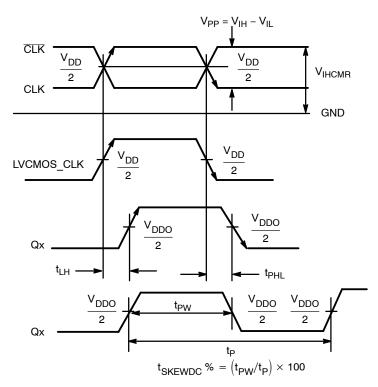


Figure 6. AC Reference Measurement

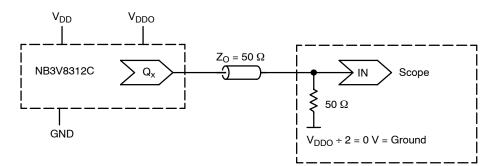
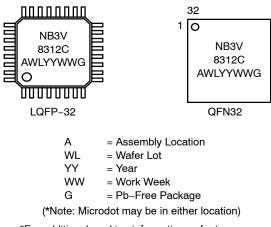


Figure 7. Typical Device Evaluation and Termination Setup – See Table 8

Table 8. TEST SUPPLY SETUP. V_{DDO} SUPPLY MAY BE CENTERED ON 0.0 V (SCOPE GND) TO PERMIT DIRECT CONNECTION INTO "50 Ω TO GND" SCOPE MODULE. V_{DD} SUPPLY TRACKS DUT GND PIN

Spec Condition:	V _{DD} Test Setup	VDDO Test Setup	GND Pin Test Setup
V_{DD} = 3.3 V ±5%, V_{DDO} = 3.3 V ±5%	+1.65 ±5%	+1.65 V ±5%	-1.65 V ±5%
V_{DD} = 3.3 V ±5%, V_{DDO} = 2.5 V ±5%	+2.05 V ±5%	+1.25 V ±5%	-1.25 V ±5%
V_{DD} = 3.3 V ±5%, V_{DDO} = 1.8 V ±5%	+2.4 V ±5%	+0.9 V ±0.1 V	–0.9 V ±0.1 V
V_{DD} = 2.5 V ±5%, $V_{DDO}O$ = 2.5 V ±5%	+1.25 V ±5%	+1.25 V ±5%	-1.25 V ±5%
V_{DD} = 2.5 V ±5%, V_{DDO} = 1.8 V ±0.2 V	+1.6 V ±5%	+0.9 V ±0.1 V	–0.9 V ±0.1 V
V_{DD} = 1.8 V ±0.2 V, V_{DDO} = 1.8 V ±0.2 V	+0.9 V ±0.1 V	+0.9 V ±0.1 V	–0.9 V ±0.1 V

MARKING DIAGRAMS*



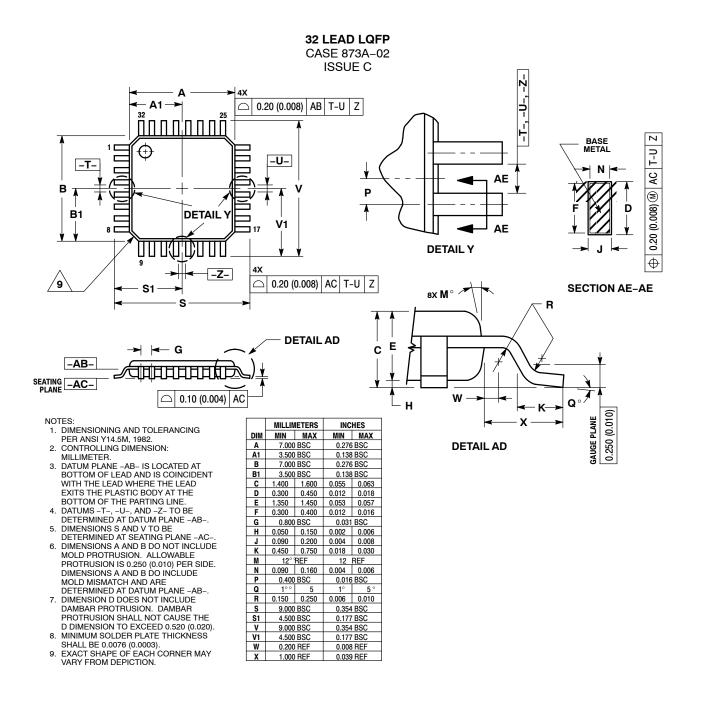
*For additional marking information, refer to Application Note AND8002/D.

ORDERING INFORMATION

Device	Package	Shipping [†]
NB3V8312CFAG	LQFP-32 (Pb-Free)	250 Units / Tray
NB3V8312CFAR2G	LQFP-32 (Pb-Free)	2000 / Tape & Reel
NB3V8312CMNG	QFN32 (Pb-Free)	74 Units / Rail
NB3V8312CMNR4G	QFN32 (Pb-Free)	1000 / Tape & Reel

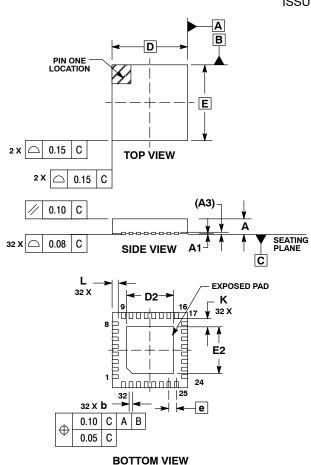
+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our T ape and Reel Packaging Specifications Brochure, BRD8011/D.

PACKAGE DIMENSIONS



PACKAGE DIMENSIONS

QFN32 5x5, 0.5P CASE 488AM **ISSUE O**

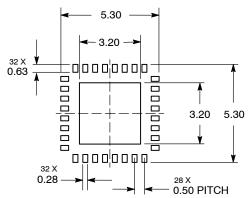


NOTES:

- DIMENSIONS AND TOLERANCING PER ASME Y14.5M, 1994.
 CONTROLLING DIMENSION: MILLIMETERS.
 DIMENSION & APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN 0.25 AND 0.30 MM TERMINAL
- COPLANARITY APPLIES TO THE EXPOSED PAD AS WELL AS THE TERMINALS. 4

	MILLIMETERS						
DIM	MIN	NOM	MAX				
Α	0.800	0.900	1.000				
A1	0.000	0.025	0.050				
A3	0.	200 REI	-				
b	0.180	0.250	0.300				
D	5	.00 BSC					
D2	2.950	3.100	3.250				
E	5	.00 BSC					
E2	2.950	3.100	3.250				
е	0.500 BSC						
К	0.200	00 00					
L	0.300	0.400	0.500				

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

ON Semiconductor and 💷 are registered trademarks of Semiconductor Components Industries, LLC (SCILLC). SCILLC owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of SCILLC's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. SCILLC reserves the right to make changes without further notice to any products herein. SCILLC makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does SCILLC assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. "Typical" parameters which may be provided in SCILLC data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. SCILLC does not convey any license under its patent rights nor the rights of others. SCILLC products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the SCILLC product could create a situation where personal injury or death may occur. Should Buyer purchase or use SCILLC products for any such unintended or unauthorized application, Buyer shall indemnify and hold SCILLC and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that SCILLC was negligent regarding the design or manufacture of the part. SCILLC is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor P.O. Box 5163, Denver, Colorado 80217 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com

N. American Technical Support: 800-282-9855 Toll Free USA/Canada Europe, Middle East and Africa Technical Support:

Phone: 421 33 790 2910 Japan Customer Focus Center Phone: 81-3-5817-1050

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative